
**Fine ceramics (advanced ceramics,
advanced technical ceramics) —
Ultraviolet photoluminescence image
test method for analysing polytypes
of boron- and nitrogen-doped SiC
crystals**

*Céramiques techniques — Méthode d'imagerie de photoluminescence
ultraviolette pour l'analyse des polytypes dans les cristaux de SiC
dopés à l'azote et au bore*





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Published in Switzerland

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